Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/568,775	HIJII ET AL.
Examiner	Art Unit
Sikyin Ip	1742

SEARCHED				
Class	Subclass	Date	Examiner	
148	420			
420	407-410	12/30/2006	SI	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NO (INCLUDING SEARCH	TES STRATEGY))
	DATE	EXMR
eDAN inventor names searched		
STN	12/30/2006	SI
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